

SCOPE: CMOS, μ P-Compatible, 12-Bit D/A Converter

<u>Device Type:</u>	<u>Generic Number:</u>
-01	MX7542S(x)/883B
-02	MX7542T(x)/883B
-03	MX7542GT(x)/883B

Case Outline(s).

<u>Outline Letter</u>	<u>Mil-Std-1835</u>	<u>Case Outline</u>	<u>Package Code</u>
Q	GDIP1-T16 or CDIP2-T16	16 Lead Cerdip	J16
E	CQCC1-N20	20-Pin Ceramic LCC	L20

Absolute Maximum Ratings: ($T_A=+25^{\circ}\text{C}$, unless otherwise noted.)

V_{DD} to AGND	0V, +7V
V_{DD} to DGND	0V, +7V
AGND to DGND	V_{DD}
DGND to AGND	V_{DD}
Digital Input Voltage to DGND	-0.3V, V_{DD}
V_{OUT1} , V_{OUT2} to AGND	-0.3V, V_{DD}
VREF to AGND	-25V to +25V
V_{RFB} to AGND	-25V to +25V

Lead Temperature (soldering, 10 seconds) $+300^{\circ}\text{C}$

Storage Temperature -65°C to $+150^{\circ}\text{C}$

Continuous Power Dissipation $T_A=+70^{\circ}\text{C}$

16 pin Cerdip(derate 10mW/ $^{\circ}\text{C}$ above $+70^{\circ}\text{C}$) 800mW

20 pin LCC(derate 9.09mW/ $^{\circ}\text{C}$ above $+70^{\circ}\text{C}$) 727mW

Junction Temperature T_J $+150^{\circ}\text{C}$

Thermal Resistance, Junction to Case, θ_{JC}

16 pin Cerdip..... 50°C/W

20 pin LCC 20°C/W

Thermal Resistance, Junction to Ambient, θ_{JA} :

16 pin Cerdip..... 100°C/W

20 pin LCC 110°C/W

Recommended Operating Conditions

Ambient Operating Range (T_A) -55°C to $+125^{\circ}\text{C}$

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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TABLE 1. ELECTRICAL TESTS:

TEST	Symbol	CONDITIONS -55°C ≤ T _A ≤ +125°C 1/ Unless otherwise specified	GROUP A Subgroup	Device type	Limits Min	Limits Max	Units
Resolution	RES	NOTE 2		All	12		Bits
Relative Accuracy	RA		1,2,3	01 02,03	-1 -0.5	1 0.5	LSB
Differential Nonlinearity	DNL	Monotonic to 11 bits Monotonic to 12 bits	1,2,3	01 02,03	-2 -1	2 1	LSB
Gain Error NOTE 3	AE		1 2,3	01,02	-12.3 -14.5	12.3 14.5	LSB
Gain Error NOTE 3	AE		1 2,3	03	-1 -2	1 2	LSB
Gain Tempco	TC _{AE}	NOTE 2		All	-5	5	ppm/°C
Power-Supply Rejection	PSRR	V _{DD} =4.75V to 5.25V (ΔGain/ΔV _{DD})	1 2,3	All	-0.005 -0.01	0.005 0.01	%/%V _{DD}
OUT1 Leakage Current	I _{OUT1}	DAC register loaded with all 0s	1 2,3	All	-1 -200	1 200	nA
OUT2 Leakage Current	I _{OUT2}	DAC register loaded with all 1s	1 2,3	All	-1 -200	1 200	nA
Output Current Settling Time NOTE 2	t _{SL}	To ±0.5LSB, OUT1 load is 100 Ω 13pF, output measured ____ from trailing edge of WR	4	All		2	μs
Feedthrough Error NOTE 2	FT	VREF=10V, 10kHz sine wave	4	All		2.5	mVp-p
Reference Input Resistance	R _{IN}		1,2,3	All	8	25	kΩ
Digital Input High Voltage	V _{IH}		1,2,3	All	3.0		V
Digital Input Low Voltage	V _{IL}		1,2,3	All		0.8	V
Digital Input Leakage Current	I _{IN}	V _{IN} =0V or V _{DD}	1,2,3	All	-1	1	μA
Digital Input Capacitance NOTE 2	C _{IN}		4	All		8	pF
Output Capacitance NOTE 2	C _{OUT1}	Digital inputs at V _{IH} , DAC register loaded with all 1s Digital inputs at V _{IL} , DAC register loaded with all 0s	4	All		260 75	pF
Output Capacitance NOTE 2	C _{OUT2}	Digital inputs at V _{IH} , DAC register loaded with all 1s Digital inputs at V _{IL} , DAC register loaded with all 0s	4	All		75 260	pF

TABLE 1. ELECTRICAL TESTS:

TEST	Symbol	CONDITIONS -55°C ≤ T _A ≤ +125°C 1/ Unless otherwise specified	GROUP A Subgroup	Device type	Limits Min	Limits Max	Units
Write Pulse Width	t _{WR}	NOTE 4	9	All	220		ns
Address to Write-Hold Time	t _{AWH}	NOTE 4	9	All	80		ns
Chip Select to Write-Hold Time	t _{CWH}	NOTE 4	9	All	100		ns
Minimum Clear Pulse Width	t _{CLR}	NOTE 4	9	All	300		ns
Chip Select to Write-Setup Time	t _{CWS}	Byte loading, NOTE 4	9	All	130		ns
Address Valid to Write-Setup Time	t _{AWS}	Byte loading, NOTE 4	9	All	180		ns
Data-Setup Time	t _{DS}	NOTE 4	9	All	350		ns
Data-Hold Time	t _{DH}	NOTE 4	9	All	65		ns
Chip Select to Write-Setup Time	t _{CWS}	DAC loading, NOTE 4	9	All	150		ns
Address Valid to Write-Setup Time	t _{AWS}	DAC loading, NOTE 4	9	All	240		ns
Supply Current	I _{DD}	Digital inputs = V _{IH} or V _{IL}	1,2,3	All		2.5	mA

NOTE 1: V_{DD}=+5V, V_{OUT1}=V_{OUT2}=0V, VREF=+10V, unless otherwise noted.

NOTE 2: Characteristics supplied for use as a typical design limit but not production tested.

NOTE 3: Measured using internal feedback resistor; includes effects of leakage current and gain TC.

NOTE 4: Timing shown in commercial datasheet.

TERMINAL CONNECTIONS:

	MX7542				
	J16	L20		J16	L20
1	OUT1	NC	11	A1	NC
2	OUT2	OUT1	12	DGND	— WR
3	AGND	OUT2	13	— CLR	A0
4	D3	AGND	14	V _{DD}	A1
5	D2	D3	15	VREF	DGND
6	D1	NC	16	R _{FB}	NC
7	D0	D2	17		— CLR
8	— CS	D1	18		V _{DD}
9	— WR	D0	19		VREF
10	A0	— CS	20		R _{FB}

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ORDERING INFORMATION:

01	J16	MX7542SQ/883B
01	L20	MX7542SE/883B
02	J16	MX7542TQ/883B
02	L20	MX7542TE/883B
03	J16	MX7542GTQ/883B
03	L20	MX7542GTE/883B

QUALITY ASSURANCE

Sampling and inspection procedures shall be in accordance with Mil-Prf-38535, Appendix A as Specified in Mil-Std-883.

Screening shall be in accordance with Method 5004 of Mil-Std-883. Burn-in test Method 1015:

1. Test Condition, A, B, C, or D.
2. $T_A = +125^{\circ}\text{C}$, minimum.
3. Interim and final electrical test requirements shall be specified in Table 2.

Quality conformance inspection shall be in accordance with Method 5005 of Mil-Std-883, Including Groups A, B, C, and D inspection.

Group A inspection:

1. Tests as specified in Table 2.
2. Selected subgroups in Table 1, Method 5005 of Mil-Std-883 shall be omitted.

Group C and D inspections:

- a. End-point electrical parameters shall be specified in Table 1.
- b. Steady-state life test, Method 1005 of Mil-Std-883.
 1. Test condition A, B, C, D.
 2. $T_A = +125^{\circ}\text{C}$, minimum.
 3. Test duration, 1000 hours, except as permitted by Method 1005 of Mil-Std-883.

TABLE 2. ELECTRICAL TEST REQUIREMENTS

Mil-Std-883 Test Requirements	Subgroups Per Method 5005, Table 1
Interim Electric Parameters Method 5004	1
Final Electrical Parameters Method 5005	1*, 2, 3
Group A Test Requirements Method 5005	1, 2, 3, 4** 9
Group C and D End-Point Electrical Parameters Method 5005	1

* PDA applies to Subgroup 1 only.

** Subgroup 4 shall be tested at initial qualification and upon redesign. Sample size will be 116 units.

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